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Art Unit 1754

Application of Vladimir V. Voronkov et al.

Serial No. 09/972,608

Filed October 5, 2001

Confirmation No. 4591

For METHOD FOR THE PRODUCTION OF LOW DEFECT DENSITY SILICON

Examiner Ngoc-Yen M. Nguyen

October 14, 2003

AMENDMENT A AND RESPONSE TO RESTRICTION

TO THE COMMISSIONER FOR PATENTS

P.O. Box 1450

Alexandria, VA 22313-1450

SIR:

In response to the restriction requirement dated August 12, 2003, please enter the following amendments:

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 7 of this paper.

Conclusion begin on page 8 of this paper.